

# Si554 REVISION D

# QUAD FREQUENCY VOLTAGE-CONTROLLED CRYSTAL OSCILLATOR (VCXO) 10 MHz TO 1.4 GHz

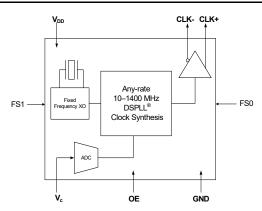
### Features

- Available with any-rate output frequencies from 10–945 MHz and selected frequencies to 1.4 GHz
- Four selectable output frequencies
- 3rd generation DSPLL<sup>®</sup> with superior jitter performance
- 3x better frequency stability than SAW-based oscillators

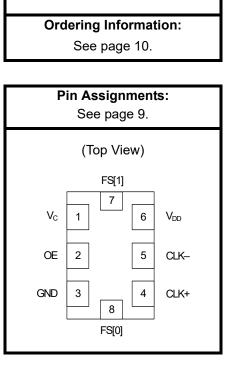
### Applications

- SONET/SDH
- xDSL
- 10 GbE LAN / WAN
- Description
- The Si554 quad-frequency VCXO utilizes Silicon Laboratories' advanced DSPLL<sup>®</sup> circuitry to provide a very low jitter clock for all output frequencies. The Si554 is available with any-rate output frequency from 10 to 945 MHz and selected frequencies to 1400 MHz. Unlike traditional VCXOs, where a different crystal is required for each output frequency, the Si554 uses one fixed crystal frequency to provide a wide range of output frequencies. This IC-based approach allows the crystal resonator to provide exceptional frequency stability and reliability. In addition, DSPLL clock synthesis provides superior supply noise rejection, simplifying the task of generating low jitter clocks in noisy environments typically found in communication systems. The Si554 IC-based VCXO is factory-configurable for a wide variety of user specifications including frequency, supply voltage, output format, tuning slope, and temperature stability. Specific configurations are factory-programmed at time of shipment, thereby eliminating the long lead times associated with custom oscillators.

### **Functional Block Diagram**



- Internal fixed crystal frequency ensures high reliability and low aging
- Available CMOS, LVPECL, LVDS, and CML outputs
- 3.3, 2.5, and 1.8 V supply options
- Industry-standard 5 x 7 mm package and pinout
- Pb-free/RoHS-compliant
  - ·
- Low jitter clock generation
- Optical modules
- Clock and data recovery



## **1. Electrical Specifications**

### Table 1. Recommended Operating Conditions

Symbol	Test Condition	Min	Тур	Мах	Units
	3.3 V option	2.97	3.3	3.63	V
V <sub>DD</sub>	2.5 V option	2.25	2.5	2.75	V
	1.8 V option	1.71	1.8	1.89	V
	Output enabled				
	LVPECL	_	120	130	
	CML	_	108	117	mA
I <sub>DD</sub>	LVDS	_	99	108	
	CMOS	_	90	98	
	Tristate mode	—	60	75	mA
	V <sub>IH</sub>	0.75 x V <sub>DD</sub>		—	V
	V <sub>IL</sub>	—		0.5	V
T <sub>A</sub>		-40	_	85	°C
		VDD     3.3 V option       VDD     2.5 V option       1.8 V option     0utput enabled       LVPECL     CML       LVDS     CMOS       Tristate mode     VIH       VIL     VIL	VDD         3.3 V option         2.97           VDD         2.5 V option         2.25           1.8 V option         1.71           Output enabled	VDD         3.3 V option         2.97         3.3           VDD         2.5 V option         2.25         2.5           1.8 V option         1.71         1.8           IDD         Output enabled          120           IDD         CML          108           IDD         LVPECL          108           IDD         LVDS          99           CMOS          90           Tristate mode          60           VIH         0.75 x VDD	$\begin{array}{c c c c c c c c c c c c c c c c c c c $

1. Selectable parameter specified by part number. See Section 3. "Ordering Information" on page 10 for further details.

**2.** OE and FS[1:0] pins include a 17 k $\Omega$  resistor to VDD.

### Table 2. V<sub>C</sub> Control Voltage Input

Parameter	Symbol	Test Condition	Min	Тур	Мах	Units
Control Voltage Tuning Slope <sup>1,2,3</sup>		10 to 90% of V <sub>DD</sub>	—	33	_	ppm/V
				45		
	K			90		
	K <sub>V</sub>			135		
				180		
				356		
Control Voltage Linearity <sup>4</sup>		BSL	-5	±1	+5	%
	L <sub>VC</sub>	Incremental	-10	±5	+10	%
Modulation Bandwidth	BW		9.3	10.0	10.7	kHz
V <sub>C</sub> Input Impedance	Z <sub>VC</sub>		500			kΩ
Nominal Control Voltage	V <sub>CNOM</sub>	@ f <sub>O</sub>		V <sub>DD</sub> /2	—	V
Control Voltage Tuning Range	V <sub>C</sub>		0		V <sub>DD</sub>	V

Notes:

1. Positive slope; selectable option by part number. See Section 3. "Ordering Information" on page 10.

For best jitter and phase noise performance, always choose the smallest K<sub>V</sub> that meets the application's minimum APR requirements. See "AN266: VCXO Tuning Slope (K<sub>V</sub>), Stability, and Absolute Pull Range (APR)" for more information.

3.  $K_V$  variation is ±10% of typical values.

4. BSL determined from deviation from best straight line fit with  $V_C$  ranging from 10 to 90% of  $V_{DD}$ . Incremental slope determined with  $V_C$  ranging from 10 to 90% of  $V_{DD}$ .



### Table 3. CLK± Output Frequency Characteristics

Parameter	Symbol	Test Condition	Min	Тур	Мах	Units
Nominal Frequency <sup>1,2,3</sup>	f <sub>O</sub>	LVDS/CML/LVPECL	10	—	945	MHz
		CMOS	10	—	160	MHz
Temperature Stability <sup>1,4</sup>		T <sub>A</sub> = –40 to +85 °C	-20		+20	
			-50		+50	ppm
			-100		+100	
Absolute Pull Range <sup>1,4</sup>	APR		±12	_	±375	ppm
Aging		Frequency drift over first year.	—	—	±3	nnm
		Frequency drift over 15 year life.	—	—	±10	ppm
Power up Time <sup>5</sup>	t <sub>osc</sub>			—	10	ms
Settling Time After FS[1:0] Change	t <sub>FRQ</sub>	Both FS[1] and FS[0] changing simultaneously			20	ms
Notes:		L		1	1	

1. See Section 3. "Ordering Information" on page 10 for further details.

2. Specified at time of order by part number. Also available in frequencies from 970 to 1134 MHz and 1213 to 1417 MHz.

3. Nominal output frequency set by  $V_{CNOM} = V_{DD}/2$ .

4. Selectable parameter specified by part number.

5. Time from power up or tristate mode to  $f_O$  (to within ±1 ppm of  $f_O$ ).

### Table 4. CLK± Output Levels and Symmetry

Parameter	Symbol	Test Condition	Min	Тур	Max	Units
LVPECL Output Option <sup>1</sup>	Vo	mid-level	V <sub>DD</sub> – 1.42	—	V <sub>DD</sub> – 1.25	V
	V <sub>OD</sub>	swing (diff)	1.1		1.9	V <sub>PP</sub>
	V <sub>SE</sub>	swing (single-ended)	0.55	—	0.95	V <sub>PP</sub>
LVDS Output Option <sup>2</sup>	V <sub>O</sub>	mid-level	1.125	1.20	1.275	V
	V <sub>OD</sub>	swing (diff)	0.5	0.7	0.9	$V_{PP}$
CML Output Option <sup>2</sup>	V	2.5/3.3 V option mid-level	—	$V_{DD} - 1.30$	—	V
	Vo	1.8 V option mid-level	_	V <sub>DD</sub> – 0.36		V
	V	2.5/3.3 V option swing (diff)	1.10	1.50	1.90	V <sub>PP</sub>
	V <sub>OD</sub>	1.8 V option swing (diff)	0.35	0.425	0.50	V <sub>PP</sub>
CMOS Output Option <sup>3</sup>	V <sub>OH</sub>	I <sub>OH</sub> = 32 mA	0.8 x V <sub>DD</sub>	—	V <sub>DD</sub>	V
	V <sub>OL</sub>	I <sub>OL</sub> = 32 mA	—	_	0.4	v
Rise/Fall time (20/80%)	t <sub>R,</sub> t <sub>F</sub>	LVPECL/LVDS/CML	—		350	ps
		CMOS with C <sub>L</sub> = 15 pF	—	1	—	ns
Symmetry (duty cycle)	SYM	LVPECL: V <sub>DD</sub> – 1.3 V (diff) LVDS: 1.25 V (diff) CMOS: V <sub>DD</sub> /2	45		55	%

Notes:

**1.** 50  $\Omega$  to V<sub>DD</sub> – 2.0 V. **2.** R<sub>term</sub> = 100  $\Omega$  (differential).

**3.** C<sub>L</sub> = 15 pF



### Table 5. CLK± Output Phase Jitter

Parameter	Symbol	Test Condition	Min	Тур	Мах	Units
Phase Jitter (RMS) <sup>1,2,3</sup>	ф	Kv = 33 ppm/V				
for F <sub>OUT</sub> <u>&gt;</u> 500 MHz	10	12 kHz to 20 MHz (OC-48)	—	0.26	—	ps
		50 kHz to 80 MHz (OC-192)	—	0.26	—	
		Kv = 45 ppm/V				
		12 kHz to 20 MHz (OC-48)	_	0.27	—	ps
		50 kHz to 80 MHz (OC-192)	—	0.26	—	
		Kv = 90 ppm/V				
		12 kHz to 20 MHz (OC-48)	—	0.32	—	ps
		50 kHz to 80 MHz (OC-192)	—	0.26	—	
		Kv = 135 ppm/V				
		12 kHz to 20 MHz (OC-48)	_	0.40	_	ps
		50 kHz to 80 MHz (OC-192)	—	0.27	—	
		Kv = 180 ppm/V				
		12 kHz to 20 MHz (OC-48)		0.49	—	ps
		50 kHz to 80 MHz (OC-192)	—	0.28	—	
		Kv = 356 ppm/V				
		12 kHz to 20 MHz (OC-48)	_	0.87	—	ps
		50 kHz to 80 MHz (OC-192)	—	0.33	—	

#### Notes:

- 1. Refer to AN255, AN256, and AN266 for further information.
- 2. For best jitter and phase noise performance, always choose the smallest K<sub>V</sub> that meets the application's minimum APR requirements. See "AN266: VCXO Tuning Slope (K<sub>V</sub>), Stability, and Absolute Pull Range (APR)" for more information.
- 3. See "AN255: Replacing 622 MHz VCSO devices with the Si550 VCXO" for comparison highlighting power supply rejection (PSR) advantage of Si55x versus SAW-based solutions.
- 4. Max jitter for LVPECL output with V<sub>C</sub>=1.65V, V<sub>DD</sub>=3.3V, 155.52 MHz. 5. Max offset frequencies: 80 MHz for F<sub>OUT</sub>  $\geq$  250 MHz, 20 MHz for 50 MHz  $\leq$  F<sub>OUT</sub> <250 MHz,
  - 2 MHz for 10 MHz  $\leq$  F<sub>OUT</sub> <50 MHz.



### Table 5. CLK± Output Phase Jitter (Continued)

Parameter	Symbol	Test Condition	Min	Тур	Max	Units
Phase Jitter (RMS) <sup>1,2,3,4,5</sup>	фJ	Kv = 33 ppm/V				
for F <sub>OUT</sub> of 125 to 500 MHz		12 kHz to 20 MHz (OC-48)	—	0.37	—	ps
		50 kHz to 80 MHz (OC-192)	—	0.33	—	-
		Kv = 45 ppm/V				
		12 kHz to 20 MHz (OC-48)	_	0.37	0.4	ps
		50 kHz to 80 MHz (OC-192)	_	0.33	—	
		Kv = 90 ppm/V				
		12 kHz to 20 MHz (OC-48)	_	0.43	—	ps
		50 kHz to 80 MHz (OC-192)	—	0.34	—	
		Kv = 135 ppm/V				
		12 kHz to 20 MHz (OC-48)	_	0.50	—	ps
		50 kHz to 80 MHz (OC-192)	—	0.34	—	
		Kv = 180 ppm/V				
		12 kHz to 20 MHz (OC-48)	_	0.59	—	ps
		50 kHz to 80 MHz (OC-192)	—	0.35	—	
		Kv = 356 ppm/V				
		12 kHz to 20 MHz (OC-48)		1.00		ps
		50 kHz to 80 MHz (OC-192)	—	0.39	—	

#### Notes:

1. Refer to AN255, AN256, and AN266 for further information.

2. For best jitter and phase noise performance, always choose the smallest Ky that meets the application's minimum APR requirements. See "AN266: VCXO Tuning Slope (K<sub>V</sub>), Stability, and Absolute Pull Range (APR)" for more information. 3. See "AN255: Replacing 622 MHz VCSO devices with the Si550 VCXO" for comparison highlighting power supply

rejection (PSR) advantage of Si55x versus SAW-based solutions.

4. Max jitter for LVPECL output with V<sub>C</sub>=1.65V, V<sub>DD</sub>=3.3V, 155.52 MHz. 5. Max offset frequencies: 80 MHz for  $F_{OUT} \ge 250$  MHz, 20 MHz for 50 MHz  $\le F_{OUT} <250$  MHz, 2 MHz for 10 MHz  $\le F_{OUT} <50$  MHz.



### Table 5. CLK± Output Phase Jitter (Continued)

Parameter	Symbol	Test Condition	Min	Тур	Мах	Units
Phase Jitter (RMS) <sup>1,2,5</sup>	фJ	Kv = 33 ppm/V				
for F <sub>OUT</sub> 10 to 160 MHz		12 kHz to 20 MHz (OC-48)	_	0.63	—	ps
CMOS Output Only		50 kHz to 20 MHz	_	0.62	—	
		Kv = 45 ppm/V				
		12 kHz to 20 MHz (OC-48)	_	0.63	—	ps
		50 kHz to 20 MHz	_	0.62	—	
		Kv = 90 ppm/V				
		12 kHz to 20 MHz (OC-48)	_	0.67	—	ps
		50 kHz to 20 MHz	_	0.66	—	
		Kv = 135 ppm/V				
		12 kHz to 20 MHz (OC-48)	_	0.74	—	ps
		50 kHz to 20 MHz	—	0.72	—	
		Kv = 180 ppm/V				
		12 kHz to 20 MHz (OC-48)	_	0.83	—	ps
		50 kHz to 20 MHz	—	0.8	—	
		Kv = 356 ppm/V				
		12 kHz to 20 MHz (OC-48)	_	1.26	_	ps
		50 kHz to 20 MHz	—	1.2	—	

Notes:

- 1. Refer to AN255, AN256, and AN266 for further information.
- 2. For best jitter and phase noise performance, always choose the smallest Ky that meets the application's minimum APR requirements. See "AN266: VCXO Tuning Slope (K<sub>V</sub>), Stability, and Absolute Pull Range (APR)" for more information.
- 3. See "AN255: Replacing 622 MHz VCSO devices with the Si550 VCXO" for comparison highlighting power supply rejection (PSR) advantage of Si55x versus SAW-based solutions.
- 4. Max jitter for LVPECL output with  $V_C$ =1.65V,  $V_{DD}$ =3.3V, 155.52 MHz.
- 5. Max offset frequencies: 80 MHz for  $F_{OUT} \ge 250$  MHz, 20 MHz for 50 MHz  $\le F_{OUT} \le 250$  MHz,
- 2 MHz for 10 MHz  $\leq$  F<sub>OUT</sub> <50 MHz.

### Table 6. CLK± Output Period Jitter

Parameter	Symbol	Test Condition	Min	Тур	Мах	Units
Period Jitter*	J <sub>PER</sub>	RMS		2		ps
		Peak-to-Peak	—	14	_	ps
*Note: Any output mode, including C	CMOS, LVPI	ECL, LVDS, CML. N = 1000 cycles.	Refer to AN	1279 for furt	her informa	ation.



Offset Frequency	74.25 MHz	491.52 MHz	622.08 MHz	Units
	90 ppm/V LVPECL	45 ppm/V LVPECL	135 ppm/V LVPECL	
	LVFECL	LVFECL	LVFECL	
100 Hz	-87	-75	-65	
1 kHz	-114	-100	-90	
10 kHz	-132	-116	-109	
100 kHz	-142	-124	-121	dBc/Hz
1 MHz	-148	-135	-134	
10 MHz	-150	-146	-146	
100 MHz	n/a	-147	-147	

Table 7. CLK± Output Phase Noise (Typical)

### **Table 8. Environmental Compliance**

The Si554 meets the following qualification test requirements.

Parameter	Conditions/Test Method
Mechanical Shock	MIL-STD-883F, Method 2002.3 B
Mechanical Vibration	MIL-STD-883F, Method 2007.3 A
Solderability	MIL-STD-883F, Method 203.8
Gross & Fine Leak	MIL-STD-883F, Method 1014.7
Resistance to Solvents	MIL-STD-883F, Method 2016
Moisture Sensitivity Level	J-STD-020, MSL 1
Contact Pads	J-STD-020, MSL 1

#### **Table 9. Thermal Characteristics**

(Typical values TA = 25 °C,  $V_{DD}$  = 3.3 V)

Parameter	Symbol	Test Condition	Min	Тур	Max	Unit
Thermal Resistance Junction to Ambient	$\theta_{JA}$	Still Air	_	84.6	_	°C/W
Thermal Resistance Junction to Case	$\theta_{JC}$	Still Air	_	38.8	_	°C/W
Ambient Temperature	T <sub>A</sub>		-40	—	85	°C
Junction Temperature	Т <sub>Ј</sub>		_		125	°C



### Table 10. Absolute Maximum Ratings<sup>1</sup>

Symbol	Rating	Units
T <sub>AMAX</sub>	85	°C
V <sub>DD</sub>	-0.5 to +1.9	V
V <sub>DD</sub>	-0.5 to +3.8	V
VI	–0.5 to V <sub>DD</sub> + 0.3	V
Τ <sub>S</sub>	-55 to +125	°C
ESD	2000	V
T <sub>PEAK</sub>	260	°C
t <sub>P</sub>	20–40	seconds
	T <sub>AMAX</sub> V <sub>DD</sub> V <sub>DD</sub> V <sub>I</sub> T <sub>S</sub> ESD T <sub>PEAK</sub>	$\begin{array}{c c} T_{AMAX} & 85 \\ \hline V_{DD} & -0.5 \text{ to } +1.9 \\ \hline V_{DD} & -0.5 \text{ to } +3.8 \\ \hline V_{I} & -0.5 \text{ to } V_{DD} + 0.3 \\ \hline T_{S} & -55 \text{ to } +125 \\ \hline ESD & 2000 \\ \hline T_{PEAK} & 260 \\ \hline \end{array}$

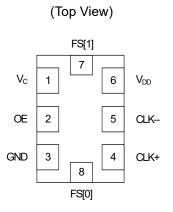
#### Notes:

1. Stresses beyond those listed in Absolute Maximum Ratings may cause permanent damage to the device. Functional operation or specification compliance is not implied at these conditions. Exposure to maximum rating conditions for extended periods may affect device reliability.

2. The device is compliant with JEDEC J-STD-020C. Refer to Si5xx Packaging FAQ available for download from www.silabs.com/VCXO for further information, including soldering profiles.



# 2. Pin Descriptions



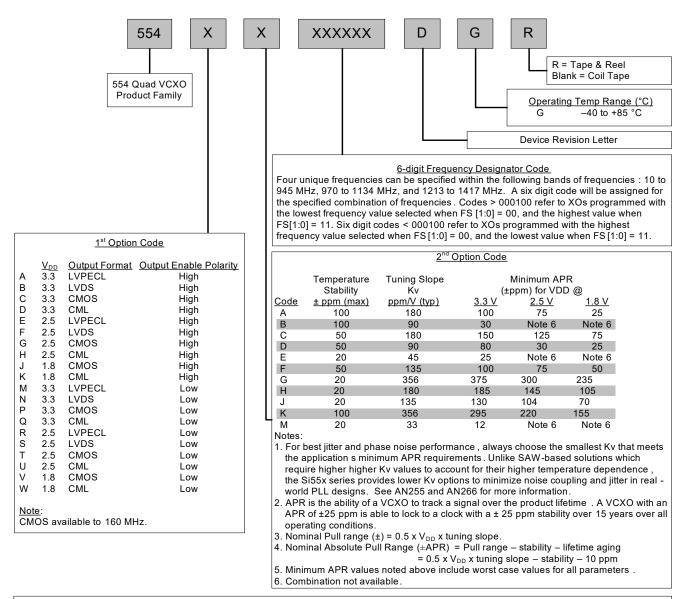


Pin	Name	Туре	Function		
1	V <sub>C</sub>	Analog Input	Control Voltage		
2	OE*	Input	Output Enable (Polarity = High): 0 = clock output disabled (outputs tri-stated) 1 = clock output enabled		
3	GND	Ground	Electrical and Case Ground		
4	CLK+	Output	Oscillator Output		
5	CLK– (N/A for CMOS)	Output	Complementary Output (N/C for CMOS)		
6	V <sub>DD</sub>	Power	Power Supply Voltage		
7	FS[1]*	Input	Frequency Select MSB		
8	FS[0]*	Input	Frequency Select LSB		
-	*Note: FS[1:0] and OE include a 17 kΩ pullup resistor to V <sub>DD</sub> . Output Enable polarity selectable at time of order. See Section 3. "Ordering Information" on page 10 for details on frequency select and OE polarity ordering options.				



## 3. Ordering Information

The Si554 supports a variety of options including frequency, temperature stability, tuning slope, output format, and  $V_{DD}$ . Specific device configurations are programmed into the Si554 at time of shipment. Configurations are specified using the Part Number Configuration chart shown below. Silicon Labs provides a web browser-based part number configuration utility to simplify this process. Refer to www.silabs.com/VCXOPartNumber to access this tool and for further ordering instructions. The Si554 VCXO series is supplied in an industry-standard, RoHS-compliant, lead-free, 8-pad, 5 x 7 mm package. Tape and reel packaging is an ordering option.



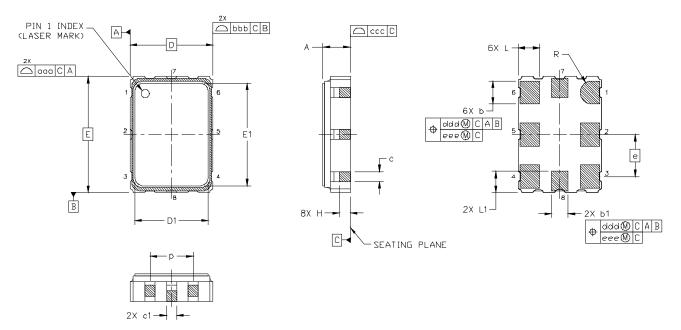
Example Part Number: 554AF000124DGR is a 5 x 7 mm Quad VCXO in an 8 pad package. Since the six digit code (000124) is > 000100, f0 is 622.08 MHz (lowest frequency), f1 is 644.53125, f2 is 657.42188, and f3 is 669.32658 MHz (highest frequency), with a 3.3 V supply, LVPECL output, and Output Enable active high polarity. Temperature stability is specified as  $\pm 50$  ppm and the tuning slope is 135 ppm/V. The part is specified for a -40 to +85 C° ambient temperature range operation and is shipped in tape and reel format .

### Figure 1. Part Number Convention



## 4. Package Outline and Suggested Pad Layout

Figure 2 illustrates the package details for the Si554. Table 12 lists the values for the dimensions shown in the illustration.



### Figure 2. Si554 Outline Diagram

### Table 12. Package Diagram Dimensions (mm)

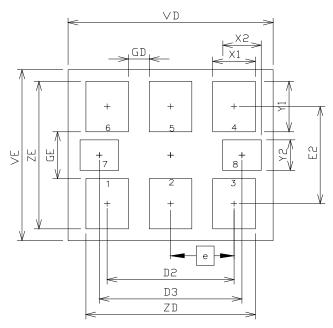
Dimension	Min	Nom	Мах
А	1.50	1.65	1.80
b	1.30	1.40	1.50
b1	0.90	1.00	1.10
С	0.50	0.60	0.70
c1	0.30		0.60
D	5.00 BSC		
D1	4.30	4.40	4.50
е	2.54 BSC		
E	7.00 BSC		
E1	6.10	6.20	6.30
Н	0.55	0.65	0.75
L	1.17	1.27	1.37
L1	1.07	1.17	1.27
р	1.80	—	2.60
R	0.70 REF		
aaa	—	_	0.15
bbb		_	0.15
CCC			0.10
ddd	—	—	0.10
eee	_	—	0.05

2. Dimensioning and Tolerancing per ANSI Y14.5M-1994.



## 5. 8-Pin PCB Land Pattern

Figure 3 illustrates the 8-pin PCB land pattern for the Si554. Table 13 lists the values for the dimensions shown in the illustration.





#### Table 13. PCB Land Pattern Dimensions (mm)

Dimension	Min	Max	
D2	5.08 REF		
D3	5.705 REF		
е	2.54 BSC		
E2	4.20 REF		
GD	0.84	—	
GE	2.00	—	
VD	8.20 REF		
VE	7.30 REF		
X1	1.70 TYP		
X2	1.545 TYP		
Y1	2.15 REF		
Y2	1.3 REF		
ZD	—	6.78	
ZE	—	6.30	

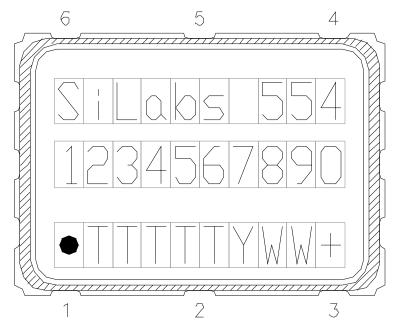
#### Note:

- **1.** Dimensioning and tolerancing per the ANSI Y14.5M-1994 specification.
- 2. Land pattern design follows IPC-7351 guidelines.
- **3.** All dimensions shown are at maximum material condition (MMC).
- 4. Controlling dimension is in millimeters (mm).



## 6. Top Marking

### 6.1. Si554 Top Marking



### 6.2. Top Marking Explanation

Line	Position	Description	
1	1–10	"SiLabs"+ Part Family Number, 554 (First 3 characters in part number)	
2	1–10	Si554: Option1+Option2+Freq(7)+Temp Si554 w/ 8-digit resolution: Option1+Option2+ConfigNum(6)+Temp	
<sup>3</sup> Trace Code			
	Position 1	Pin 1 orientation mark (dot)	
	Position 2	Product Revision (D)	
	Position 3–6	Tiny Trace Code (4 alphanumeric characters per assembly release instructions)	
	Position 7	Year (least significant year digit), to be assigned by assembly site (ex: 2007 = 7)	
	Position 8–9	Calendar Work Week number (1–53), to be assigned by assembly site	
	Position 10	"+" to indicate Pb-Free and RoHS-compliant	



## **DOCUMENT CHANGE LIST**

### **Revision 0.6 to Revision 1.0**

- Updated Table 4 on page 3.
  - Updated 2.5 V/3.3 V and 1.8 V CML output level specifications.
- Updated Table 5 on page 4.
  - Removed the words "Differential Modes: LVPECL/LVDS/CML" in the footnote referring to AN256.
  - Added footnotes clarifying max offset frequency test conditions.
  - Added CMOS phase jitter specs.
- Updated Table 10 on page 8.
  - Separated 1.8 V, 2.5 V/3.3 V supply voltage specifications.
  - Updated ESD HBM sensitivity rating.
- Updated and clarified Table 8 on page 7
  - Added "Moisture Sensitivity Level" and "Contact Pads" rows.
- Updated 6. "Top Marking" on page 13 to reflect specific marking information (previously, figure was generic).
- Updated 4. "Package Outline and Suggested Pad Layout" on page 11.
  - Added cyrstal impedance pin in Figure 2 on page 11 and Table 12 on page 11.
- Reordered spec tables and back matter to conform to data sheet quality conventions.

### **Revision 1.0 to Revision 1.1**

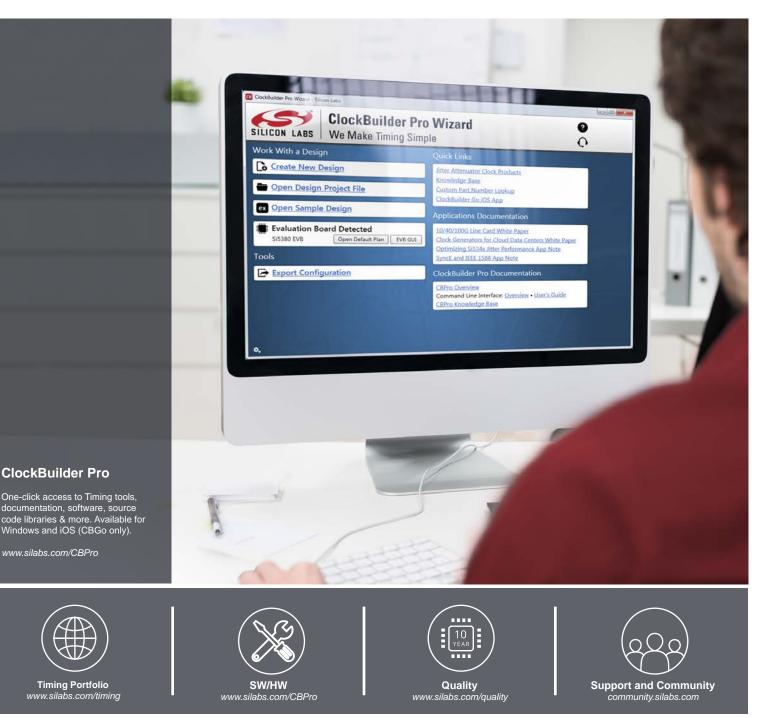
 Added Table 9, "Thermal Characteristics," on page 7.

### **Revision 1.1 to Revision 1.2**

June, 2018

 Changed "Trays" to "Coil Tape" in section 3. "Ordering Information".





#### Disclaimer

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